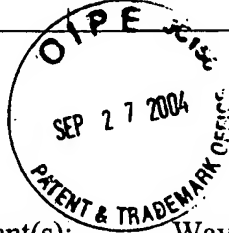


JPW/92B 2856



655 Montgomery Street, Suite 1800 San Francisco, Ca 94111  
tel 415.318.1160 fax 415.693.0194

Applicant(s): Wayne G. Renken

Title: Process Condition Sensing Wafer and Data Analysis System

Application No.: 10/056,906

Filing Date: January 24, 2002

Examiner: Charles D. Garber

Group Art Unit: 2856

Docket No.: SENS.005US0

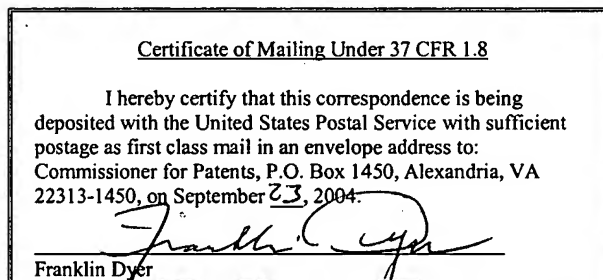
Conf. No.: 2359

Mail Stop Amendment  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith are the following documents in the above-identified application:

- (1) Amendment (12 pages); and
- (2) Return Postcard.



Respectfully submitted,

Peter A. Gallagher  
Reg. No.47,584

9/23/04  
Date



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Wayne G. Renken  
Title: Process Condition Sensing Wafer And Data Analysis System  
Application No.: 10/685,550 Filing Date: October 14, 2003  
Examiner: Charles D. Garber Group Art Unit: 2856  
Docket No.: SENS.005US1 Conf. No.: 4924

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Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

AMENDMENT

Sir:

This is in response to the non-final Office Action dated June 29, 2004, setting a period for response expiring on September 29, 2004.

Claim Amendments are reflected in the listing of claims, which begins on page 2 of this paper.

Drawing Amendments are not being made.

Specification Amendments are not being made.

Remarks begin on page 7 of this paper.